

November
5th & 6th, 2015

Advanced Tools for Nanoscopic Materials Characterization

Venue

S.N. Bose National Centre for Basic Sciences

Block – JD, Sector – III, Salt Lake
Kolkata – 700098

Organized by

S.N. Bose National Centre for Basic Sciences

Kolkata
&

Icon Analytical Equipment Pvt. Ltd.

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Course fees : Rs. 3000/-
Last Date of Registration :
20th October, 2015

Topic of Interest:

- Nanolithography
- Nanofabrication
- Atomic Force Microscopy
- Scanning electron microcopy
- Micro structural analysis using Transmission electron microscope
- X-Ray Photo electron Spectroscopy & Scanning Auger Spectroscopy
- Cross sectional specimen preparation using Focused Ion Beam for interface Physics study
- Energy filtered imaging (EFTEM) and Electron energy loss spectroscopy (EELS)

Invited Speakers:

Prof. Srikumar Banerjee, *BARC, Mumbai*
Prof. N. Ravishankar, *IISC, Bangalore*
Daniel Phifer, *FEI*
Dr. Yogesh Jeyaram, *Bruker*
Wolfgang Betz, *Physical Electronics (XPS)*
Prof. Vikram Jayaram, *IISC, Bangalore*
Dr. Daniel Goran, *Bruker, AXS*
Prof. A. K. Raychaudhuri, *SNBNCBS, Kolkata*
Eugene Bekker, *FEI*

Convener

Dr. Barnali Ghosh (Saha)

Co-Convener

Prof. P.K. Mukhopadhyay

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